

# STC5NF30V

# N-CHANNEL 30V - 0.027 $\Omega$ - 5A TSSOP8 2.7V-DRIVE STripFET<sup>TM</sup> II POWER MOSFET

TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	ΙD
STC5NF30V	30 V	< 0.031 Ω ( @ 4.5 V ) < 0.035 Ω ( @ 2.7 V )	5 A

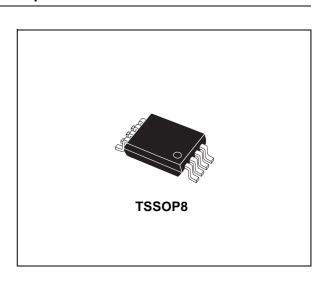
- TYPICAL  $R_{DS}(on) = 0.027 \Omega @ 4.5 V$
- TYPICAL  $R_{DS}(on) = 0.031 \Omega @ 2.7 V$
- ULTRA LOW THRESHOLD GATE DRIVE (2.7 V)
- STANDARD OUTLINE FOR EASY AUTOMATED SURFACE MOUNT ASSEMBLY

#### **DESCRIPTION**

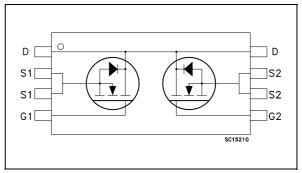
This Power MOSFET is the latest development of STMicroelectronis unique "Single Feature Size™" strip-based process. The resulting transistor shows extremely high packing density for low onresistance, rugged avalanche characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.

#### **APPLICATIONS**

- DC MOTOR DRIVE
- DC-DC CONVERTERS
- BATTERY MANAGEMENT IN NOMADIC EQUIPMENT
- POWER MANAGEMENT IN PORTABLE/DESKTOP PCs



#### **INTERNAL SCHEMATIC DIAGRAM**



#### **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter Value		Unit
V <sub>DS</sub>	Drain-source Voltage (V <sub>GS</sub> = 0)	30	V
$V_{DGR}$	Drain-gate Voltage ( $R_{GS} = 20 \text{ k}\Omega$ )	20	V
V <sub>GS</sub>	Gate- source Voltage	± 12	V
I <sub>D</sub>	Drain Current (continuous) at T <sub>C</sub> = 25°C	5	Α
I <sub>D</sub>	Drain Current (continuous) at T <sub>C</sub> = 100°C	3	Α
I <sub>DM</sub> (●)	Drain Current (pulsed)	20	Α
P <sub>tot</sub>	Total Dissipation at T <sub>C</sub> = 25°C	1.5	W

<sup>(•)</sup> Pulse width limited by safe operating area.

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# STC5NF30V

# THERMAL DATA

,   1, 1, 1, 1, 1, 1, 1, 1, 1, 1, 1, 1, 1,	°C/W °C/W °C	100 83.5 -55 to 150 -55 to 150		Operating Junction Temperature	Ť <sub>j</sub>
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<sup>(\*)</sup> When Mounted on FR-4 board with 1 inch² pad, 2 oz of Cu and t  $\leq$  10 sec (\*\*) When Mounted on minimum recommended footprint

# **ELECTRICAL CHARACTERISTICS** (T<sub>case</sub> = 25 °C unless otherwise specified)

# OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0$	30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current (V <sub>GS</sub> = 0)	$V_{DS} = Max Rating$ $V_{DS} = Max Rating T_C = 125^{\circ}C$			1 10	μA μA
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 12V			±100	nA

# ON (\*)

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$	$I_D = 250 \ \mu A$	0.6			V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	V <sub>GS</sub> = 4.5 V V <sub>GS</sub> = 2.7 V	$I_D = 2.5 A$ $I_D = 2.5 A$		0.027 0.031	0.031 0.035	$\Omega$

# **DYNAMIC**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> (*)	Forward Transconductance	$V_{DS}=15 \text{ V}$ $I_{D}=2.5 \text{ A}$		9.5		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 15V f = 1 MHz, V_{GS} = 0$		460 200 50		pF pF pF

# **ELECTRICAL CHARACTERISTICS** (continued)

#### **SWITCHING ON**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub> t <sub>r</sub>	Turn-on Delay Time Rise Time	$\begin{aligned} V_{DD} &= 10 \text{ V} & I_D &= 2.5 \text{ A} \\ R_G &= 4.7 \ \Omega & V_{GS} &= 4.5 \text{ V} \\ \text{(Resistive Load, Figure 1)} \end{aligned}$		7 33		ns ns
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V <sub>DD</sub> = 16V I <sub>D</sub> = 5A V <sub>GS</sub> =4.5V (see test circuit, Figure 2)		8.5 1.8 2.4	11.5	nC nC nC

#### **SWITCHING OFF**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
$t_{d(off)} \ t_{f}$	Turn-off Delay Time Fall Time	$\begin{aligned} &V_{DD} = 10 \text{ V} & I_{D} = 2.5 \text{ A} \\ &R_{G} = 4.7\Omega, &V_{GS} = 4.5 \text{ V} \\ &(\text{Resistive Load, Figure 1}) \end{aligned}$		27 10		ns ns
$t_{ ext{d(Voff)}} \ t_{ ext{f}} \ t_{ ext{c}}$	Off-voltage Rise Time Fall Time Cross-over Time	$\begin{aligned} &V_{clamp} = 16 \text{ V} & I_D = 5 \text{ A} \\ &R_G = 4.7\Omega, &V_{GS} = 4.5 \text{ V} \\ &(\text{Inductive Load, Figure 3}) \end{aligned}$		26 11 21		ns ns ns

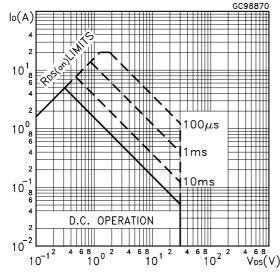
#### SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
I <sub>SD</sub> I <sub>SDM</sub> (•)	Source-drain Current Source-drain Current (pulsed)					5 20	A A
V <sub>SD</sub> (*)	Forward On Voltage	I <sub>SD</sub> = 5 A	V <sub>GS</sub> = 0			1.2	V
t <sub>rr</sub> Q <sub>rr</sub> IRRM	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 5 A$ $V_{DD} = 10 V$ (see test circu	di/dt = $100A/\mu s$ $T_j = 150^{\circ}C$ it, Figure 3)		26 13 1		ns nC A

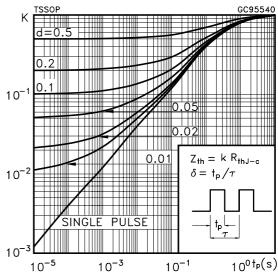
<sup>(\*)</sup>Pulsed: Pulse duration = 300 µs, duty cycle 1.5 %.

(•)Pulse width limited by safe operating area.

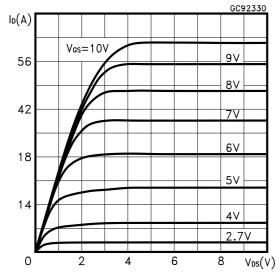
#### Safe Operating Area



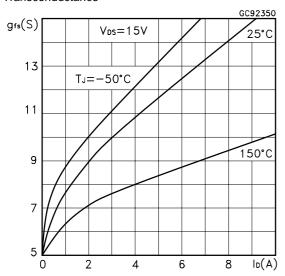
# Thermal Impedance



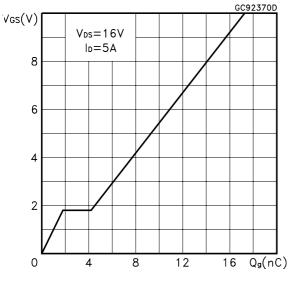
#### **Output Characteristics**



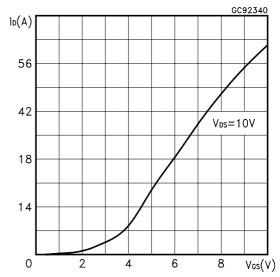
#### Transconductance



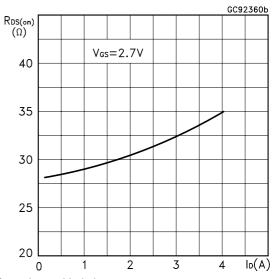
Gate Charge vs Gate-source Voltage



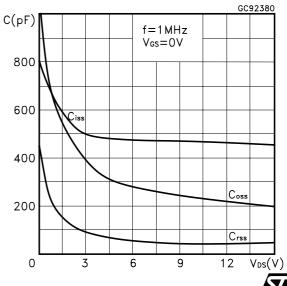
#### Transfer Characteristics



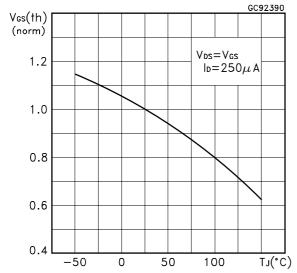
Static Drain-source On Resistance



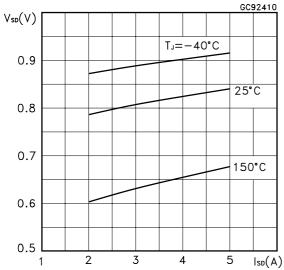
# Capacitance Variations



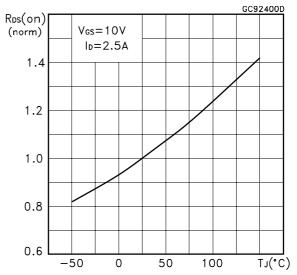
# Normalized Gate Threshold Voltage vs Temperature



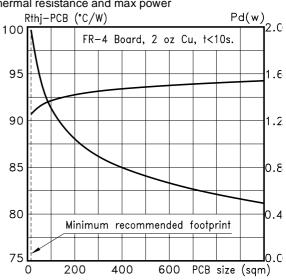
#### Source-drain Diode Forward Characteristics



#### Normalized on Resistance vs Temperature



#### Thermal resistance and max power



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Fig. 1: Switching Times Test Circuits For Resistive Load

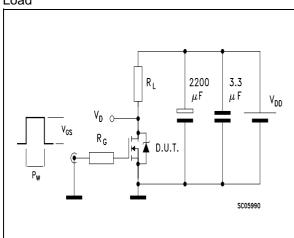


Fig. 2: Gate Charge test Circuit

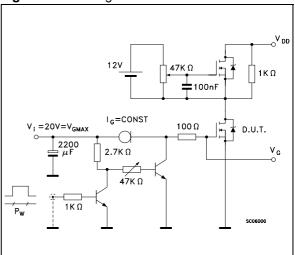
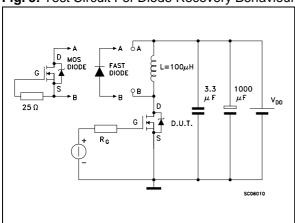
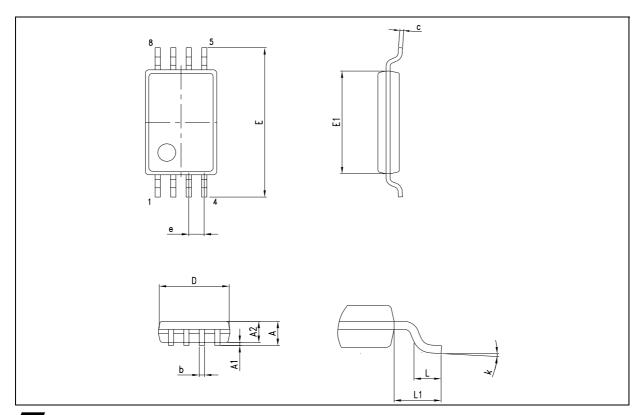


Fig. 3: Test Circuit For Diode Recovery Behaviour



# **TSSOP8 MECHANICAL DATA**

DIM.		mm. inch.			mm.			
DIIVI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.		
Α	1.05		1.20	0.041		0.047		
A1	0.05		0.15	0.002		0.006		
A2	0.80		1.05	0.032		0.041		
b	0.19		0.30	0.008		0.012		
С	0.090		0.20	0.003		0.007		
D	2.90		3.10	0.114		0.122		
Е	6.20		6.60	0.240		0.260		
E1	4.30		4.50	0.170		0.177		
е		0.65			0.025			
L	0.45		0.75	0.018		0.030		
L1		1.00			0.039			
k	00		80	0.192		0.208		



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